

Sir C.V. RAMAN KRISHNAN INTERNATIONAL RESEARCH CENTER

Consultancy charges for Test/Characterization

| SI No. | Characterization | | Consultancy charges | |
|--------|---|-------------|--|--|
| | | | Educational Institutions (Rs.) | Industry (Rs.) |
| 1. | X - ray diffractometer | Normal Scan | 300.00 | 750.00 |
| | | Slow Scan | 600.00 | 1500.00 |
| 2. | Fourier Transform Infrared Spectrophotometer 75.00 150.00 | | 75.00 | 150.00 |
| 3. | Scanning Electron Microscope | | 900.00 | 1800.00 |
| | Scanning Electron Microscope with EDAX | | 1200.00 | 2000.00 |
| | Scanning Electron Microscope, EDAX with Mapping | | 1500.00 | 2500.00 |
| 4. | Atomic Absorption 4 Spectrophotometer | | 150.00 per sample per element (plus sample preparation charges Rs.50.00) | 250.00 per sample per element (plus sample preparation charges Rs.50.00) |
| 5. | V-Visible Spectrophotometer | | 75.00 | 150.00 |